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Indian Standard

SPECIFICATION FOR QUARTZ CRYSTAL UNITS USED FOR FREQUENCY CONTROL AND SELECTION

PART 5 SERIES CX FOR OSCILLATORS

Section 3 Quartz Crystal Unit Type CX-03

- **0.** General This standard shall be read in conjunction with IS: 8271 (Part 1)-1981 'Specification for quartz crystal units used for frequency control and selection: Part 1 General requirements and tests (first revision).
- 1. Outline and Dimensions Holder outline shall conform to type CX [see IS:4570 (Part 6)-1984 Specification for crystal unit holders: Part 6 Metal, solder seal, two pin crystal unit holder types CX].
- 2. Marking See 8 of IS: 8271 (Part 1)-1981.
- 3. Construction and Workmanship See 7 of IS: 8271 (Part 1)-1981.
- 4. Test Schedule and Detail Requirements
- 4.1 General Conditions for Test See 9.2 of IS: 8271 (Part 1)-1981.
- 4.2 Test Schedule The sequence and grouping of type, routine and acceptance tests shall be as per 9.1 of IS: 8271 (Part 1)-1981.
- 4.3 Detail Requirements The detail requirements applicable to this particular type of crystal unit shall be as specified in Table 1.

Characteristics	Requirements
i) Type of holder	CX (See 1)
ii) Frequency range	2.2 to 20 MHz
ii) Frequency tolerance; Operating temperature range	± 50 ppm
iv) Load capacitance	30·0 ± 0·5 pF
v) Mode of oscillation	Fundamental
vi) Operating temperature range	55 to 105°C
vii) Test set, calibration values and rated drive level	See Table 2
iii) Capacitance shunt	7 pF maximum
ix) Resonance resistance	See Table 3
x) Shock [As per 9.15 (Severity A) of IS: 8271 (Part 1)-1981] a) Frequency change permitted	± 5 ppm
b) Resonance resistance change permitted	± 10 percent
xi) Vibration [As per 9.16.1 (Severity A) of IS: 8271 (Part 1)-1981]	— · · · · · · · · · · · · · · · · · · ·
 a) Frequency change permitted b) Resonance resistance change permitted 	± 5 ppm ± 10 percent
xii) Temperature cycling: a) Frequency change permitted b) Resonance resistance change permitted	± 5 ppm ± 10 percent
xiii) Ageing: Frequency change permitted	5 ppm

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TABLE 2 TEST SET, CALIBRATION VALUES AND RATED DRIVE LEVEL

[Table 1 (vii)]

Si No.	Frequency Range	Calibration Values			Rated Drive	Test Set
	nange	Resistance	Crystal Current	Resistor Voltage Drop	Level	
(1)	(2)	(3)	(4)	(5)	(6)	(7)
	MHz	ohms	mA	V	mW	
i)	From 2.2 to 5.1	50	10	_	5·0±1·0)	
ii)	Over 5:1 to 7:5	22	15		5·0±1·0 }	TS-330/TSM
iii)	Over 7.5 to 10	13	20		5·0±1·0	
iv)	Over 10 to 20	10	_	0.22	5·0±1·0	TS-683/TSM

TABLE 3 RESONANCE RESISTANCE

[Table 1 (ix)]

Frequency	Ra	nge	Maximum Resonance Resistance
(1)			(2)
MHz			ohms
From 2·2 t	0	3.0	360
Over 3.0 t	o	3.75	180
Over 3.75 t	to	4.75	120
Over 4.75 t	ot	6	75
Over 6	to	7	50
Over 7	to	10	30
Over 10	to	20	25

EXPLANATORY NOTE

This standard covers the requirements of crystal unit, quartz, style QC-22 of JSS 50906 (1971) 'Detail specification for crystal unit, quartz styles QC-20, QC-22, QC-23 and QC-26' issued by the Directorate of Standardization, Ministry of Defence (India).